

PCN# : P34HA

Issue Date : Jun. 04, 2013

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

Implementation of change:

Expected First Shipment Date for Changed Product : Sep. 02, 2013

Expected First Date Code of Changed Product :1331

Description of Change (From):

Manufacturing source for SOT23 package located in Jiangyin City, Jiangsu Province, China. Molding compound type, E'dale ELL-2K1, is used.

Description of Change (To):

Manufacturing source for SOT23 package located in Chuzhou City, Anhui Province, China. Low-halogen molding compound type, E'dale ELER-8-100HFE, will be used.

Reason for Change:

Fairchild's China Subcontractor moved their manufacturing facility from Jiangyin City to Chuzhou City. In addition, in support of Fairchild's Green Initiative, qualified low-halogen molding compound type will be used for production at new site. The package outline drawings of the affected products remain unchanged. All of the affected products are fully compliant to all published data sheet specifications and this change will have no impact on their electrical performance. Quality and reliability will remain at the highest standards already demonstrated with Fairchild's existing products.



Affected Product(s):

LM431SACM32X	LM431SACM3X	LM431SBCM32X
LM431SBCM3X	LM431SCCM32X	LM431SCCM3X

Qualification Plan	Device	Package	Process	No. of Lots
Q20130064	MMBTA92	SOT23	Bipolars	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
Test				
High Temperature Reverse	150C, 80% BV	JESD22-A108	1000 hrs	0/77
Bias Test				
High Temperature Storage	150C	JESD22-A103	1000 hrs	0/77
Life				
Power Cycle	Delta 100C, 2 Min	MIL-STD-750-	10000	0/77
	cycle	1036	cycles	
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130064	FDV301N	SOT23	LV Mosfet	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Gate Bias Test	150C, 80% of BV	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750- 1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130064	FDV304P	SOT23	LV Mosfet	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Gate Bias Test	150C, 80% of BV	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750- 1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130064	LM431SACM32X	SOT23	Std Linear	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Op Life	125C, Vbias= 35V	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

NOTE: The affected products in PCN# P336A and P34HA were qualified together under the same qualification plan: Q20130064.